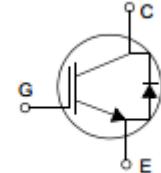


IGBT

Features

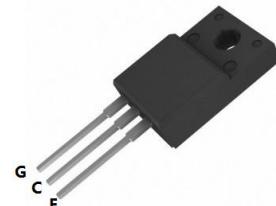
- 650V 20A, $V_{CE(sat)(typ.)} = 1.70$ V@20A
- Field Stop IGBT Technology.
- 10 μ s Short Circuit Capability.
- Square RBSOA.
- Positive VCE (on) Temperature Coefficient.



TO-220F

Benefits

- High Efficiency for Motor Control.
- Rugged Performance.
- Excellent Current Sharing in Parallel Operation



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{CES}	Collector-Emitter Voltage	650	V
V_{GES}	Gate-Emitter Voltage	± 30	V
I_C	Continuous Collector Current ($T_C=25$ °C)	40	A
	Continuous Collector Current ($T_C=100$ °C)	20	A
I_{CM}	Pulsed Collector Current (Note 1)	80	A
I_F	Diode Continuous Forward Current ($T_C=100$ °C)	20	A
I_{FM}	Diode Maximum Forward Current (Note 1)	80	A
t_{sc}	Short Circuit Withstand Time	10	us
I_{SC}	Short Circuit Current	150	A
P_D	Maximum Power Dissipation ($T_C=25$ °C)	37	W
P_D	Maximum Power Dissipation ($T_C=100$ °C)	15	W
T_J	Operating Junction Temperature Range	-55 to +150	°C
T_{STG}	Storage Temperature Range	-55 to +150	°C

Thermal Characteristics

Symbol	Parameter	Max.	Units
$R_{th j-c}$	Thermal Resistance, Junction to case for IGBT	3.3	°C / W
$R_{th j-c}$	Thermal Resistance, Junction to case for Diode	4.3	°C / W
$R_{th j-a}$	Thermal Resistance, Junction to Ambient	80	°C / W

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{CES}	Collector-Emitter Breakdown Voltage	$V_{\text{GE}}=0\text{V}, I_{\text{C}}=250\mu\text{A}$	650	-	-	V
I_{CES}	Collector-Emitter Leakage Current	$V_{\text{CE}}=650\text{V}, V_{\text{GE}}=0\text{V}$	-	-	250	μA
I_{GES}	Gate Leakage Current, Forward	$V_{\text{GE}}=30\text{V}, V_{\text{CE}}=0\text{V}$	-	-	100	nA
	Gate Leakage Current, Reverse	$V_{\text{GE}}=-30\text{V}, V_{\text{CE}}=0\text{V}$	-	-	-100	nA
$V_{\text{GE}(\text{th})}$	Gate Threshold Voltage	$V_{\text{GE}}=V_{\text{CE}}, I_{\text{C}}=250\mu\text{A}$	4.0	-	5.5	V
$V_{\text{CE}(\text{sat})}$	Collector-Emitter Saturation Voltage	$V_{\text{GE}}=15\text{V}, I_{\text{C}}=20\text{A}$	-	1.70		V
Q_g	Total Gate Charge	$V_{\text{CC}}=480\text{V}$ $V_{\text{GE}}=15\text{V}$ $I_{\text{C}}=20\text{A}$	-	79		nC
Q_{ge}	Gate-Emitter Charge		-	11		nC
Q_{gc}	Gate-Collector Charge		-	43		nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{CC}}=400\text{V}$ $V_{\text{GE}}=15\text{V}$ $I_{\text{C}}=20\text{A}$ $R_{\text{G}}=10\Omega$ Inductive Load	-	16	-	ns
t_r	Turn-on Rise Time		-	27	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time		-	113	-	ns
t_f	Turn-off Fall Time		-	26	-	ns
Eon	Turn-on Switching Loss		-	0.49	-	mJ
Eoff	Turn-off Switching Loss	$T_C=25^\circ\text{C}$	-	0.31	-	mJ
Cies	Input Capacitance		-	980	-	pF
Coes	Output Capacitance		-	130	-	pF
Cres	Reverse Transfer Capacitance	$f = 1\text{MHz}$	-	60	-	pF
R_{Gint}	Integrated gate resistor	$f=1\text{MHz}; V_{\text{pp}}=1\text{V}$		2.30		Ω

Electrical Characteristics of Diode ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_F	Diode Forward Voltage	$I_F=20\text{A}$	-	2.3		V
t_{rr}	Diode Reverse Recovery Time	$V_{\text{CE}}=400\text{V}$ $I_F=20\text{A}$	-	42		ns
I_{rrm}	Diode peak Reverse Recovery Current		-	7.6		A
Q_{rr}	Diode Reverse Recovery Charge	$dI_F/dt = 500\text{A}/\mu\text{s}$	-	186		nC

Notes:

- Repetitive Rating: Pulse width limited by maximum junction temperature

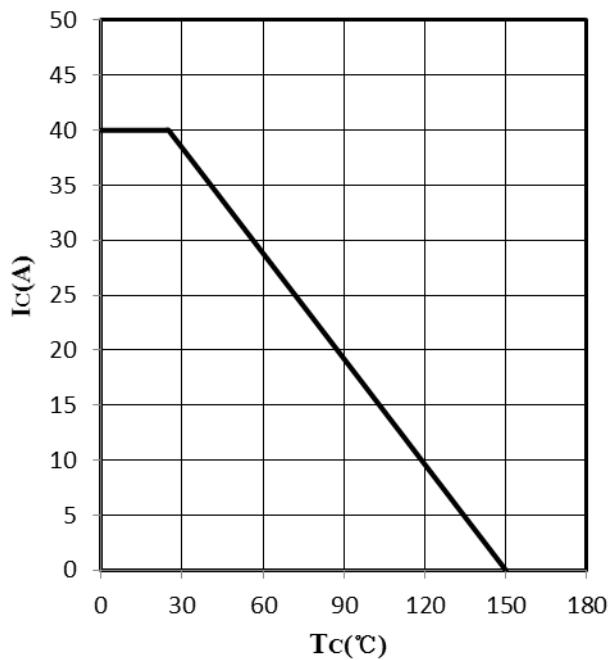


Fig 1. DC Collector current as a function of case temperature ($V_{GE} \geq 15V$, $T_j \leq 150^{\circ}C$)

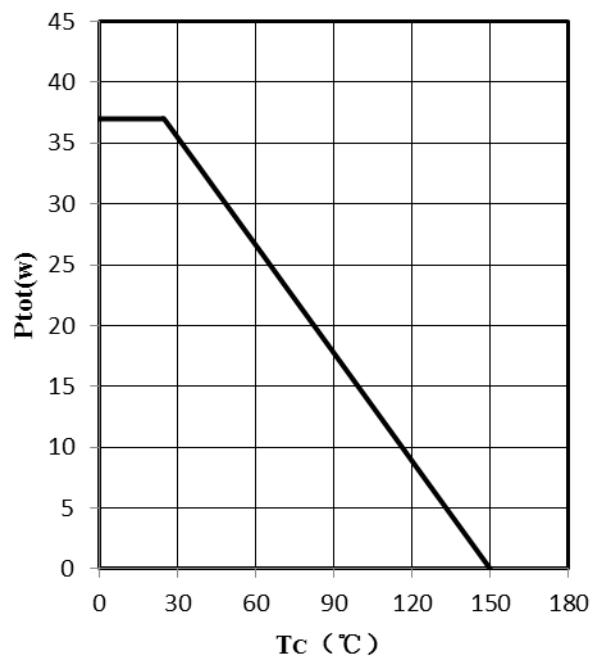


Fig 2. Power dissipation as a function of case temperature ($T_j \leq 150^{\circ}C$)

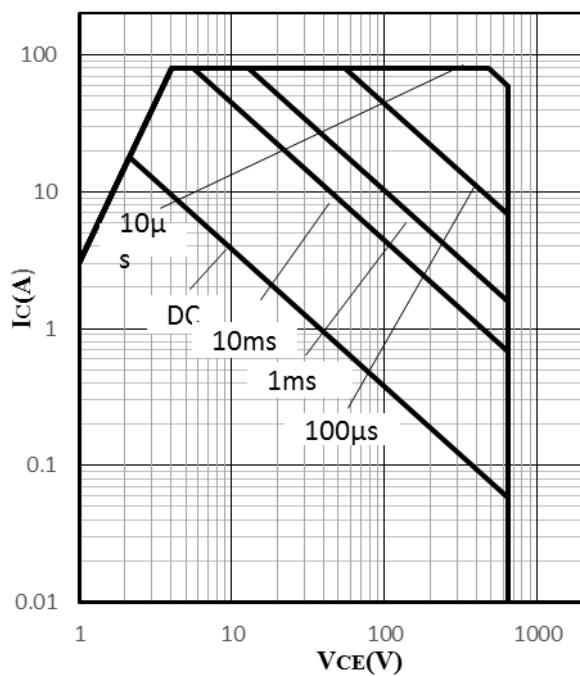


Fig 3. IGBT Forward safe operation area

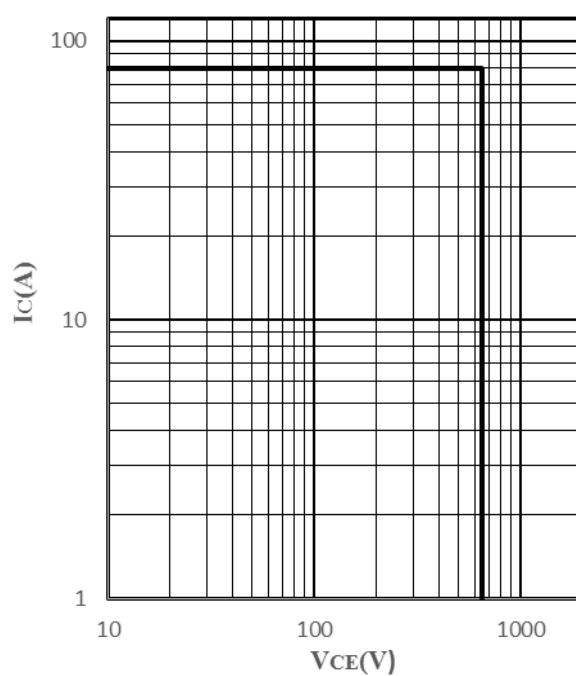


Fig 4. IGBT Reverse safe operation area

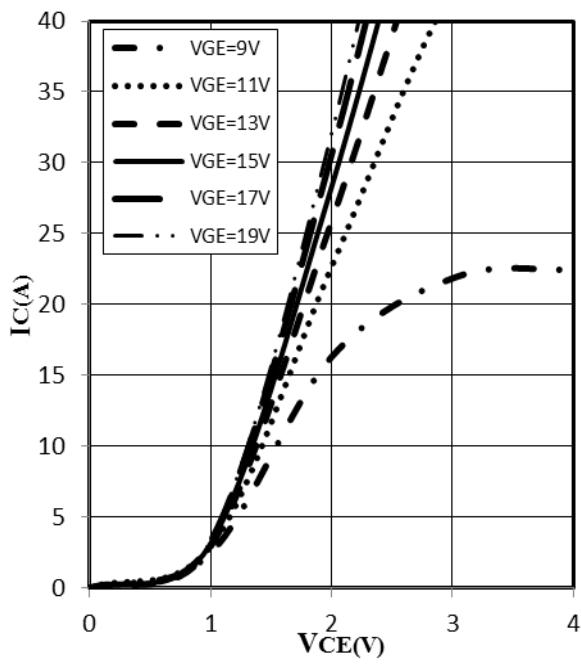


Fig 5. Typical output characteristic ($T_j=25^\circ\text{C}$)

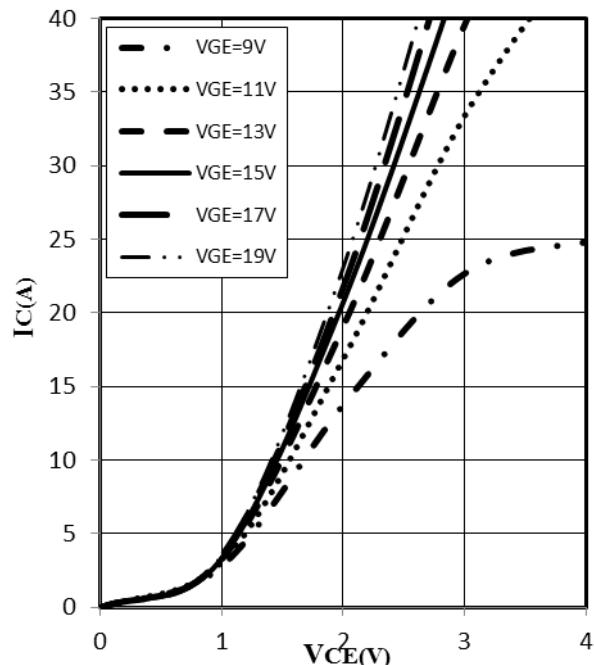


Fig 6. Typical output characteristic ($T_j=125^\circ\text{C}$)

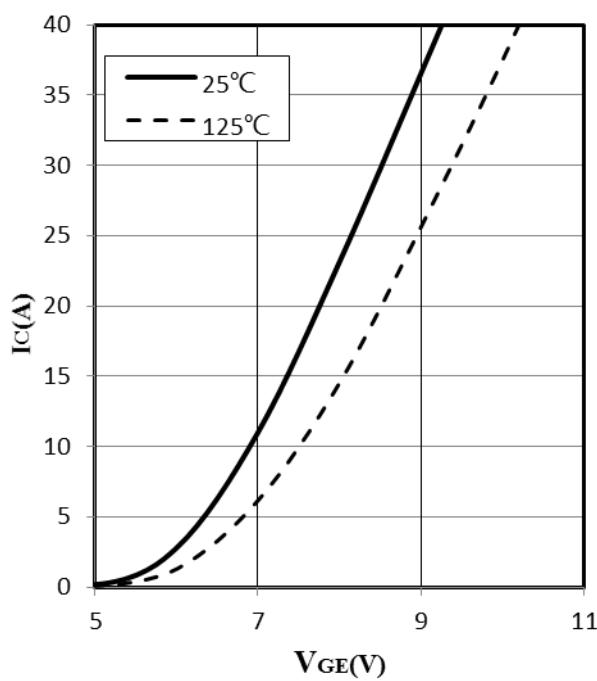


Fig 7. Typical transfer characteristic ($V_{CE}=20\text{V}$)

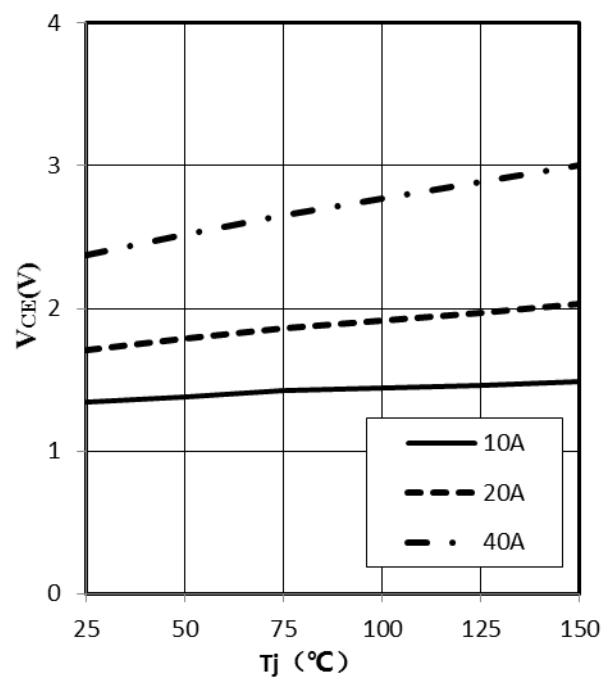


Fig 8. Typical collector-emitter saturation voltage as a function of junction temperature ($V_{GE}=15\text{V}$)

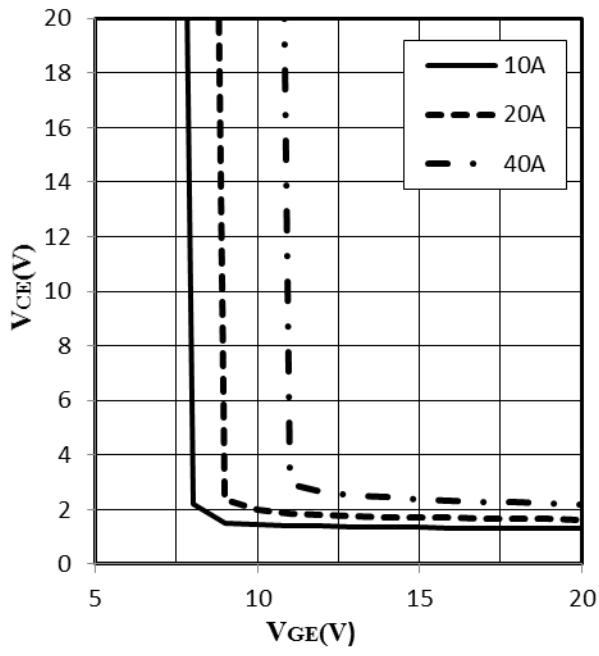


Fig 9. Typical collector-emitter saturation voltage as a function of V_{GE} ($T_j=25^\circ C$)

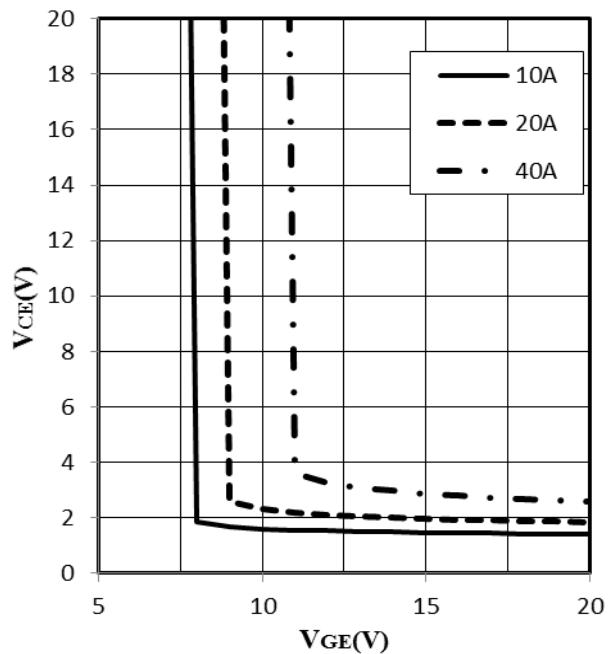


Fig 10. Typical collector-emitter saturation voltage as a function of V_{GE} ($T_j=125^\circ C$)

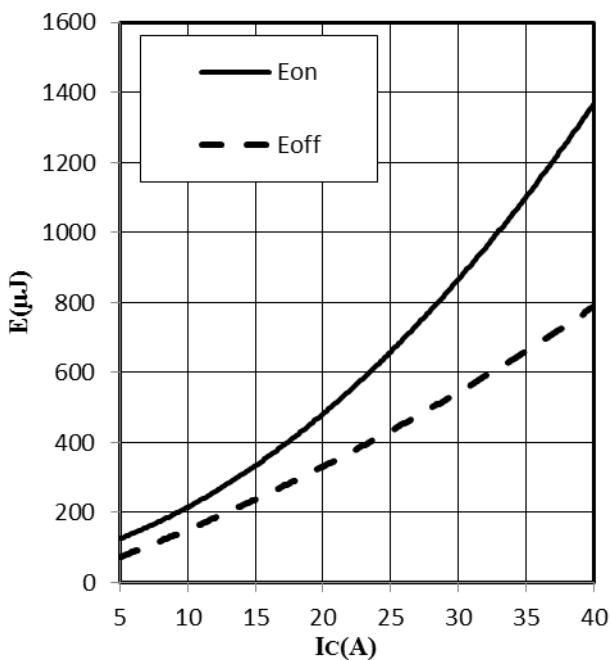


Fig 11. Typical switch energy as a function of I_C (inductive load, $T_j=25^\circ C$, $V_{CE}=400V$, $V_{GE}=15V$, $R_G=10\Omega$)

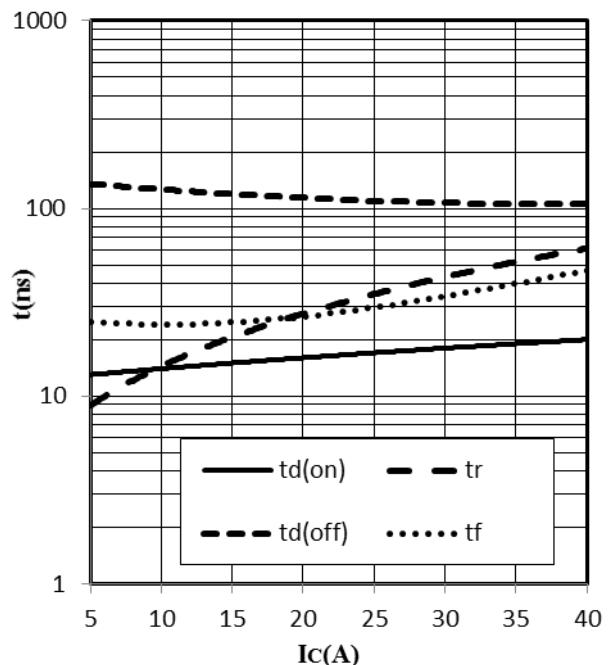


Fig 12. Typical switch time as a function of I_C (inductive load, $T_j=25^\circ C$, $V_{CE}=400V$, $V_{GE}=15V$, $R_G=10\Omega$)

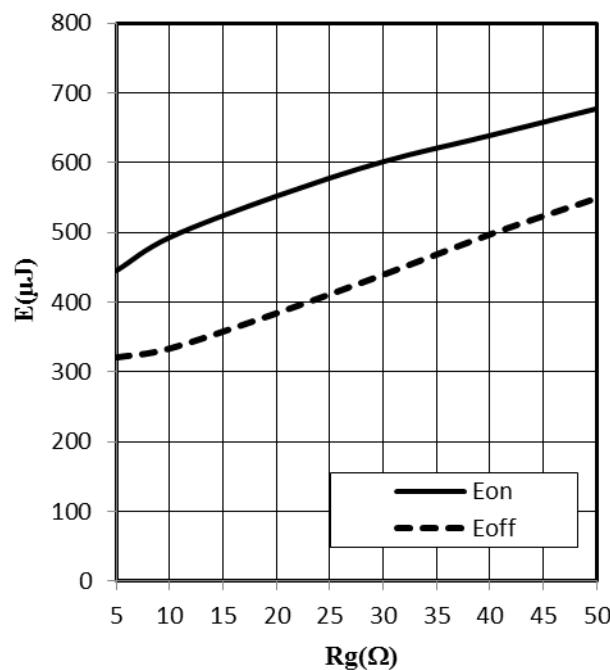


Fig 13. Typical switch energy as a function of R_g
(inductive load, $T_j=25^\circ\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15\text{V}$, $I_c=20\text{A}$)

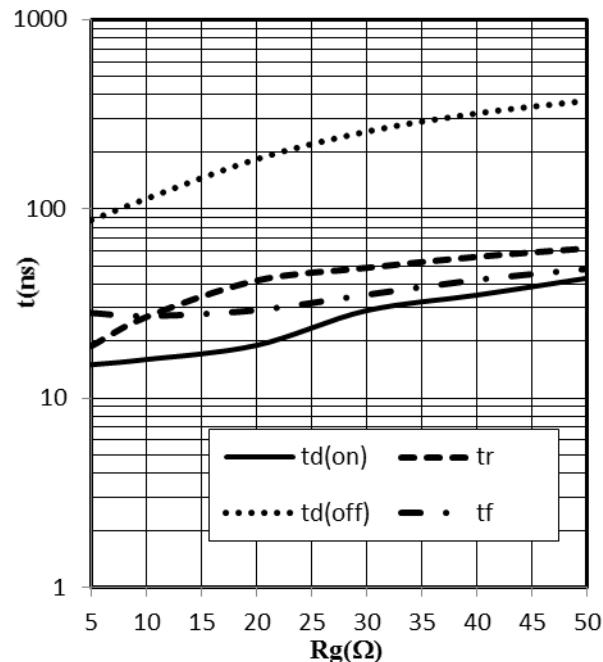


Fig 14. Typical switch time as a function of R_g
(inductive load, $T_j=25^\circ\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15\text{V}$, $I_c=20\text{A}$)

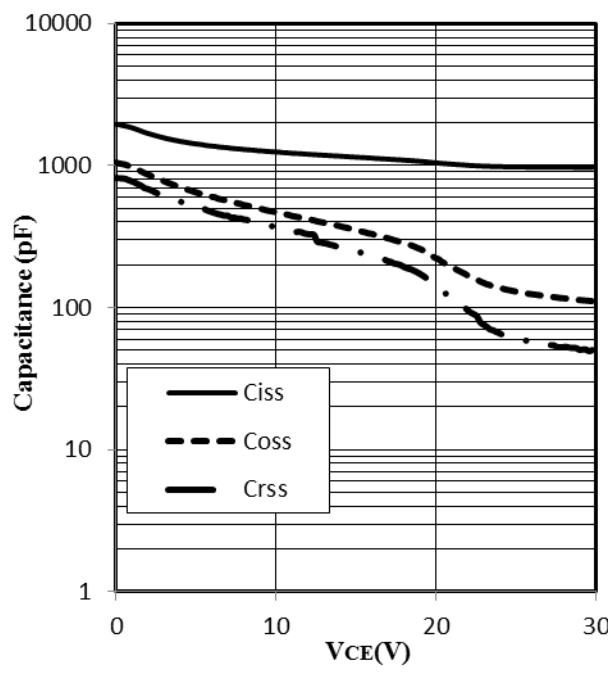


Fig 15. Typical capacitance as a function of collector-emitter voltage ($V_{GE}=0\text{V}$, $f=1\text{MHz}$)

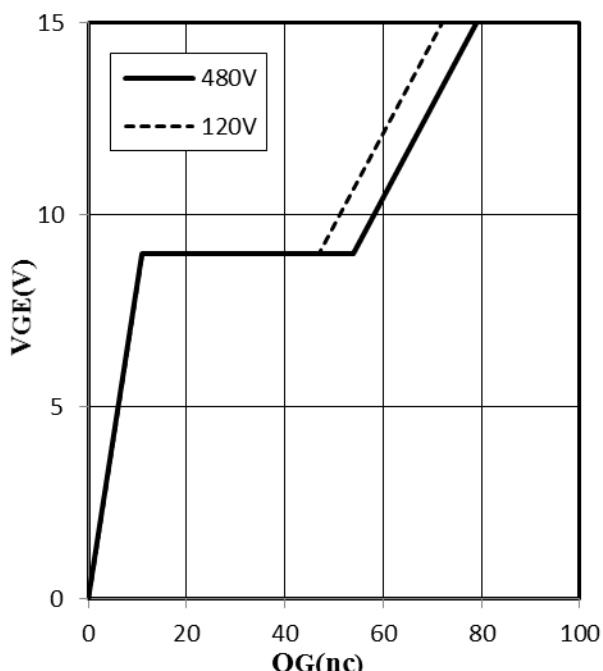


Fig 16. Typical gate charge ($I_c=20\text{A}$)

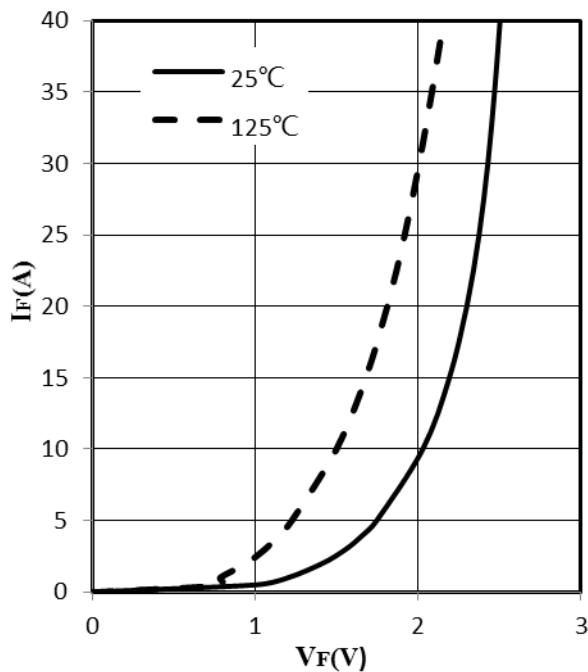


Fig 17. Typical diode forward current as a function of forward voltage

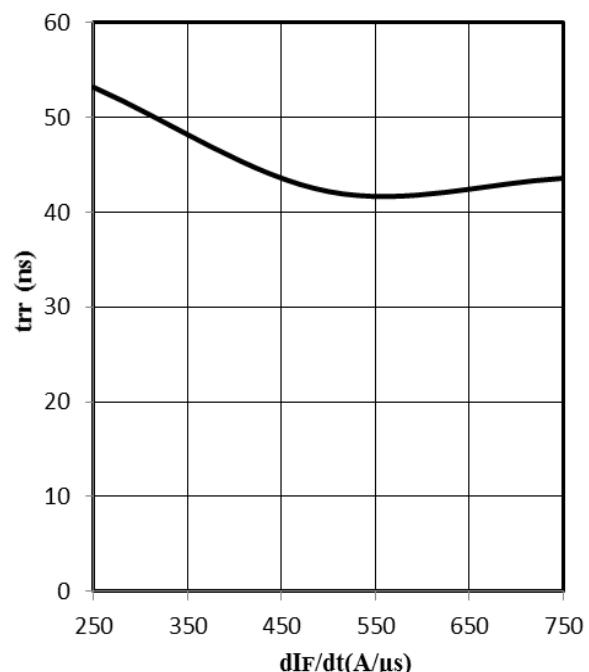


Fig 18. Typical trr as a function of dI_F/dt

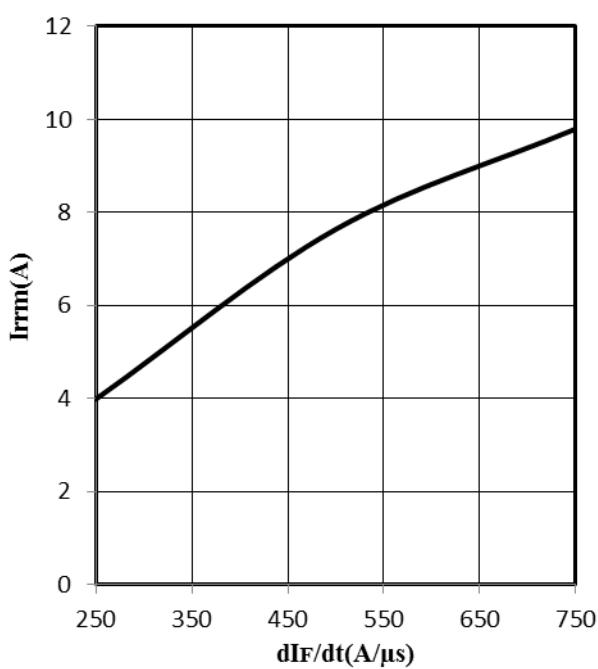


Fig 19. Typical I_{rrm} as a function of dI_F/dt

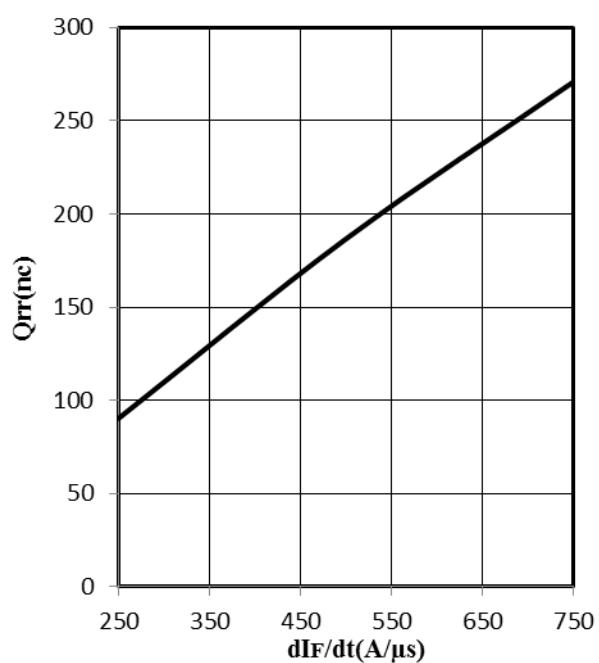


Fig 20. Typical Q_{rr} as a function of dI_F/dt

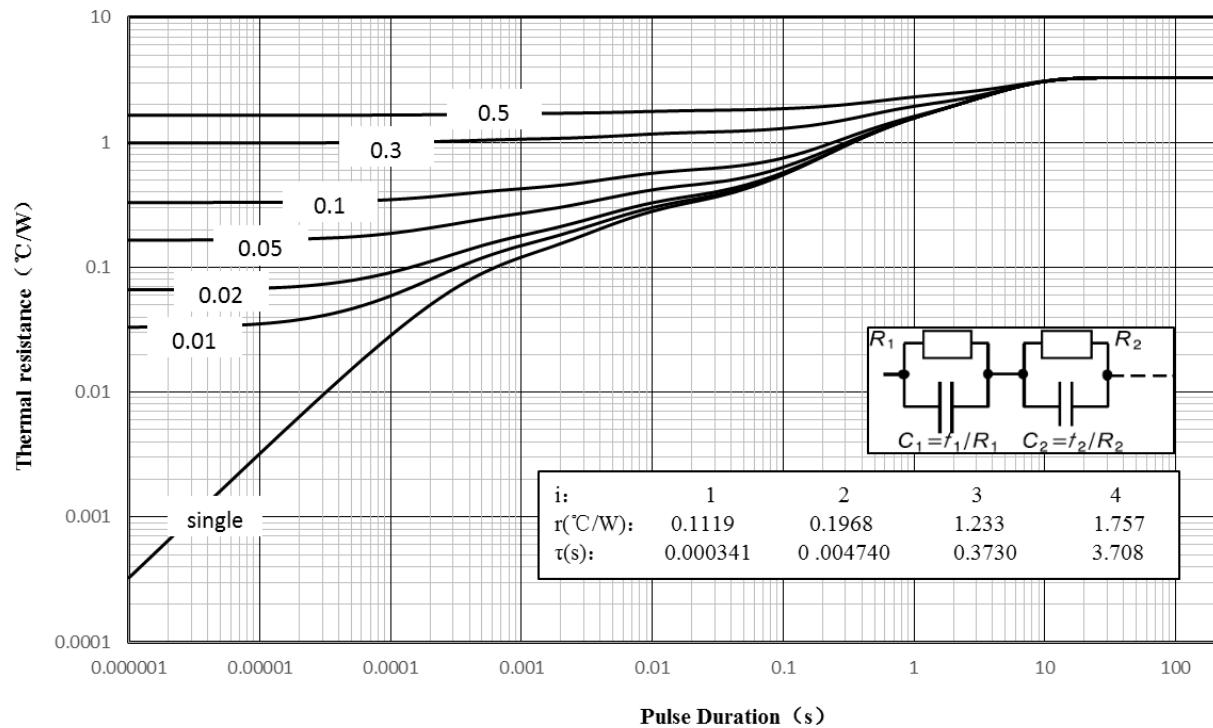


Fig 21. IGBT transient thermal resistance($D=\tau_p/T$)